REMARKS/ARGUMENTS

Claims 43, 51, 52, 54, 56, 57, 60, 61, 63-65, and 68 have been amended, and claims 44-47, 50, 58, 66, 67, and 69-73 have been canceled without prejudice. In addition, new claims 75-85 have been added. Claims 43, 48, 49, 51-57, 59-65, 68, 74-83 are pending in the application. (Claims 1-42 were previously canceled.) Applicants respectfully request reexamination and reconsideration of the application.

Applicants acknowledge with appreciation the Examiner's indication that claims 56 and 57 are allowable over the prior art of record. Applicants assert that claims 56 and 57 remain allowable and that, as discussed below, all of the other claims pending in the application are also allowable.

Claims 43-48, 50-55, 59-61, 63, 64, 66-69, and 71-74 were rejected as anticipated by US Patent No. 3,939,414 to Roch ("Roch"). In addition, claims 50, 65-68, 73, and 74 were rejected as "clearly anticipated" by US Patent No. 4,969,826 to Grabbe ("Grabbe"), and claims 43-55 and 58-74 were rejected as "clearly anticipated" by US Patent No. 5,521,522 to Abe et al. ("Abe"). Applicants respectfully traverse these rejections.

Independent claim 43 is directed to a "tested semiconductor device produced by a process" that includes using a probe card assembly comprising a probe card, a probe substrate, and an interposer. The interposer is disposed between the probe card and the probe substrate and includes "a plurality of compliant elongate interconnection elements extending from opposite sides of said interposer and providing compliant electrical connections through said interposer between ones of said electrical contacts of said probe card and ones of said probe elements." A non-limiting example of such an interposer is shown as element 504 in Figure 5 of the instant application.

In the Office Action, Roch's housing 22 was equated with the interposer of claim 43. Roch's housing 22, however, completely lacks "a plurality of compliant elongate interconnection elements extending from opposite sides of said interposer and providing compliant electrical connections through said interposer between ones of said electrical contacts of said probe card and ones of said probe elements." Indeed, no electrical connections of any kind through Roch's housing 22 are provided, nor would there be any reason to modify Roch to include compliant elongate interconnection elements through the housing 22. Therefore, independent claim 43, as

well as dependent claims 48, 49, 51-57, 59-65, 68, 74-81 (all of which depend from claim 43), patentably distinguish over Roch.

Independent claim 43 also includes "a moveable element disposed to alter an orientation of said probe substrate with respect to said probe card." Abe lacks "a moveable element disposed to alter an orientation of said probe substrate with respect to said probe card," and nothing in Abe suggests adding such a moveable element. Certainly, no moveable element is provided for altering an orientation of Abe's probe card 5 (or 7) with respect to Abe's performance board 92. Therefore, independent claim 43, as well as dependent claims 48, 49, 51-57, 59-65, 68, 74-81 (all of which depend from claim 43), patentably distinguish over Abe.

As mentioned above, independent claim 43 includes a "probe card assembly" and includes the step of testing a plurality of semiconductor devices. Grabbe's "high density connector for an IC chip carrier" is not a probe card assembly, and Grabbe does not disclose testing semiconductor devices. Thus, Grabbe would not seem to be relevant to claim 43. Therefore, independent claim 43, as well as dependent claims 48, 49, 51-57, 59-65, 68, 74-81 (all of which depend from claim 43), also patentably distinguish over Grabbe.

Independent claim 82 includes features that are generally similar to those of claim 43 discussed above. Therefore, independent claim 82, as well as claim 83 (which depends from claim 82), also patentably distinguish over Roch, Abe, and Grabbe.

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In view of the foregoing, Applicants submit that all of the claims are allowable and the application is in condition for allowance. If the Examiner believes that a discussion with Applicants' attorney would be helpful, the Examiner is invited to contact the undersigned at (801) 323-5934.

Respectfully submitted,

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